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The following document is being circulated for vote at CENELEC level :

*Work Item Number* : 70268  
*CLC reference* : prEN IEC 61000-4-6:2022  
*Reference document* : IEC 61000-4-6 ED5 (77B/856/CDV) (EQV)  
*Title* : Electromagnetic compatibility (EMC) - Part 4-6: Testing and measurement techniques - Immunity to conducted disturbances, induced by radio-frequency fields  
*Technical Body* : CLC/TC 210  
*IEC/TC* : IEC/SC 77B  
*Procedure* : Parallel Vote on CDV  
*BT decision* : -  
*Submission date* : 2022-04-15  
*Deadline* : 2022-07-08  
*doa* : dor + 3 months  
*dop* : dor + 9 months  
*dow* : dor + 36 months  
*Directive(s)* : EMC\_2014 (2014/30/EU)  
*Mandate(s)* : M/490  
*Supersedes* : EN 61000-4-6:2014 + AC:2015  
*Available languages* : -  
*Document link* : -  
*(Acting) Secretary* : Ms Nyomee Hla-Shwe Tun  
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*Permanent Delegate* : -  
*c.c* : -  
*CCMC comment* : -

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# 77B/856/CDV

## COMMITTEE DRAFT FOR VOTE (CDV)

PROJECT NUMBER:

**IEC 61000-4-6 ED5**

DATE OF CIRCULATION:

**2022-04-15**

CLOSING DATE FOR VOTING:

**2022-07-08**

SUPERSEDES DOCUMENTS:

**77B/843/CD, 77B/854/CC**

|   |   |
|---|---|
| IEC SC 77B : HIGH FREQUENCY PHENOMENA   |   |
| SECRETARIAT:<br>France  | SECRETARY:<br>Mr Franck GRUFFAZ   |
| OF INTEREST TO THE FOLLOWING COMMITTEES:<br>TC 61,CIS/F,CIS/H   | PROPOSED HORIZONTAL STANDARD:<br><input type="checkbox"/><br>Other TC/SCs are requested to indicate their interest, if any, in this CDV to the secretary. |
| FUNCTIONS CONCERNED:<br><input checked="" type="checkbox"/> EMC <input type="checkbox"/> ENVIRONMENT <input type="checkbox"/> QUALITY ASSURANCE <input type="checkbox"/> SAFETY   |   |
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TITLE:

**Electromagnetic compatibility (EMC) - Part 4-6: Testing and measurement techniques - Immunity to conducted disturbances, induced by radio-frequency fields**

PROPOSED STABILITY DATE: 2027

NOTE FROM TC/SC OFFICERS:

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